

FORM PTO-1449		US Dept. of Commerce Patent and Trademark Office	ATTORNEY DOCKET NO. 2771-161 CON	SERIAL NO. Not Yet Assigned
INFORMATION DISCLOSURE STATEMENT  (use several sheets if necessary)		APPLICANT Tischler, et al.		
		FILING DATE August 14, 2001	GROUP	

**U.S. PATENT DOCUMENTS**

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
M)	AA	4,727,047	2/23/88	Bozler et al.	437	089	
/	AB	4,931,132	6/5/90	Aspnes et al.			
/	AC	4,622,083	11/11/86	Shih			
/	AD	5,334,277	8/94	Nakamura	117	102	
/	AE	3,598,526	8/10/71	Humi et al.	23	192	
/	AF	3,634,149	1/11/72	Knippenberg	148	175	
/	AG	3,326,820	6/20/67	Cuomo et al.	252	478	
/	AH	5,954,874	9/21/99	Hunter	117	84	
/	AI	5,919,305	4/6/99	Solomon	117	90	
/	AJ	5,846,844	12/8/98	Akasaki et al.	437	21	
/	AK	5,385,862	1/31/95	Moustakas	437	107	
/	AL	3,829,556	8/13/74	Logan et al.	423	409	
/	AM	5,146,465	9/8/92	Khan et al.	372	45	
M)	AN	5,433,169	7/18/95	Nakamura	117	102	

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
M)	AO	JP56-59700A	10/17/79	JAPAN				
M)	AP	62183399	6/22/87	JAPAN				

**OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)**

M)	AQ	Derwent Abstract of JP 56-59700A; Matsushita Elec Ind Co.; "Gallium Nitride Thin Single Crystal Film"; 1979
/	AR	"Defect reduction in GaAs epitaxial layers using a GaAsP-InGaAs strained-layer superlattice," Tischler et al., Appl. Phys. Lett. 46(3), pp. 294-296 (1985)
/	AS	"GaN, AlN, and InN: A review," Strite, S., and Morkoc, J. Vac. Sci. Technol. B 10 (4), 1237-1266 (1992)
M)	AT	"Current Status of GaN and Related Compounds as Wide-Gap Semiconductors," Matsuoka, T., J. Crystal Growth 124, 433-438 (1992)

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EXAMINER <i>Mark S</i>	DATE CONSIDERED 6/30/2005
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EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
M>	AU	5,239,188	8/24/93	Takeuchi et al.	257	76	
	AV	5,006,914	4/9/91	Beetz, Jr.	357	61	
	AW	5,373,171	12/13/94	Imai et al.	257	77	
	AX	3,922,703	11/25/75	Pankove	357	17	
M>	AY	4,985,742	12/15/91	Pankove	357	34	

#### FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO

#### OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)


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EXAMINER <i>Matt J</i>	DATE CONSIDERED 6/30/2005
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